Issue Classification



Application No.	Applicant(s)
09/661,979	HAIK, STEPHEN MICHEL
Examiner	Art Unit

1881   88  8 18  8 8  16 8  8    8  8   8   18   1								Alexis Wachtel 1764												
				- 6		IS	SSU	E C	LAS	SIFI	CAT	TION				, Š	, 9, 1 1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1			
7		ORIGIN	IAL"	127. 1				di. 3.	1572	1.4		CROSS	REFEREN	ICE(S	12.50	W. 3	100			
CLASS SUBCLASS CLASS							9: 13	SUBCLASS (ONE SUBCLASS PER BLOCK)												
202 227						700	2	70	28	282		0 0 m						3 5		
INTERNATIONAL CLASSIFICATION						201		1	30		N.	Å.								
C 1	0	G 9/14			208	4	8r	48	q	131		DIG.1					43.00	61.		
C 1			1	203	1		2									<b>公</b> 集第				
													100					1 1 1 1		
			7			14	100		\$ 1.00 m		4 437		10000				1 10			
			3 7			200 A	96-27													
My Walk 3-4-04 (Assistant Examiner) (Date)							Glenn Caldarola Supervisory Patent Examiner Technology Center 1700 3/7/0\(\text{(Primary Examiner)}\)							Total Claims Allowed: 3						
(Jegal Instruments Examiner) (Date)					Su	O.G. O.G. Print Fig														
$\boxtimes$	Claim	s renu	mbere	d in th	e sam	e orde	er as p	reser	ited by	y appl	cant		PA			D		□R	.1.47	
Final	Original		Final	Original	1	Final	Original		Final	Original		Final	Original		Final	Original		Final	Original	
1	1	-		31		· · · · · · · · ·	61	1	<b></b>	91			121			151			181	
2	2			32			62			92	]		122			152			182	
3	3			33			63	]		93			123	ļ		153			18	
	4	_		34	}		64			94			124			154		<u> </u>	18	
	5	4		35		<u> </u>	65			95	1		125			155			18	
	6	4		36	-	<u> </u>	66			96	{		126	}		156			18	
	7	4		37 38	}		67 68			97 98	-		127 128	}		157 158			18 18	
	9	$\dashv$		39	{		69			99	1		129	ł		159			18	
	10	$\dashv$		40	1	<b></b>	70	1		100	1		130			160			19	
	11	1		41			71	1		101	1		131			161			19	
	12	7		42	1		72	1		102	1		132	-		162			19	
	13	1		43	1		73	]		103	]		133			163			19	
	14			44			74	]		104	]		134			164			19	
	15	_		45			75			105			135			165		<u> </u>	19	
	16	4	<u> </u>	46			76		ļ	106		<u> </u>	136			166		<u> </u>	19	
	17	_		47			77			107	1	<b> </b>	137			167		<u> </u>	19	